

CYRUSTEK ES5106 A/D CONVERTER Datasheet

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The ES 5106 is a low power monolithic CMOS 3 1/2 digit LCD display A/D converter. The single chip ES 5106 provides all necessary active devices which contains the internal clock, voltage reference, seven segment decoders, LCD display drivers and a back plane driver. The improved internal zener reference voltage circuit gives the analog common a small temperature coefficient of 60 ppm°C typically.

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1 · GENERAL DESCRIPTION

The ES 5106 is a low power monolithic CMOS 3 1/2 digit LCD display A/D converter. The single chip ES 5106 provides all necessary active devices which contains the internal clock, voltage reference, seven-segment decoders, LCD display drivers and a back plane driver. The improved internal zener reference voltage circuit gives the analog common a small temperature coefficient of 60 ppm/°C typically.

The high accuracy characteristics of the ES5106 perform very low linearity error and rollover error. The high input impedance ($>10^{12}\Omega$) and low input leakage current (1pA typical) give the ES5106 a good application in the field of high impedance circuit measurement. The differential input and reference are suitable for measuring bridge transducer or ohms by using ratiometric method.

The dual slope conversion technique makes the ES5106 a good normal and common mode rejection ratio. With a suitable oscillator frequency, the ES5106 has a high rejection of 50HZ, 60HZ and 400HZ line frequency noise.

With single power supply, a few passive components and a LCD display, ES5106 can be built as a high performance panel meter. Existing TSC7106 or ICL7106 based systems may be upgraded without changing external, passive component values.



2 · FEAUTRES

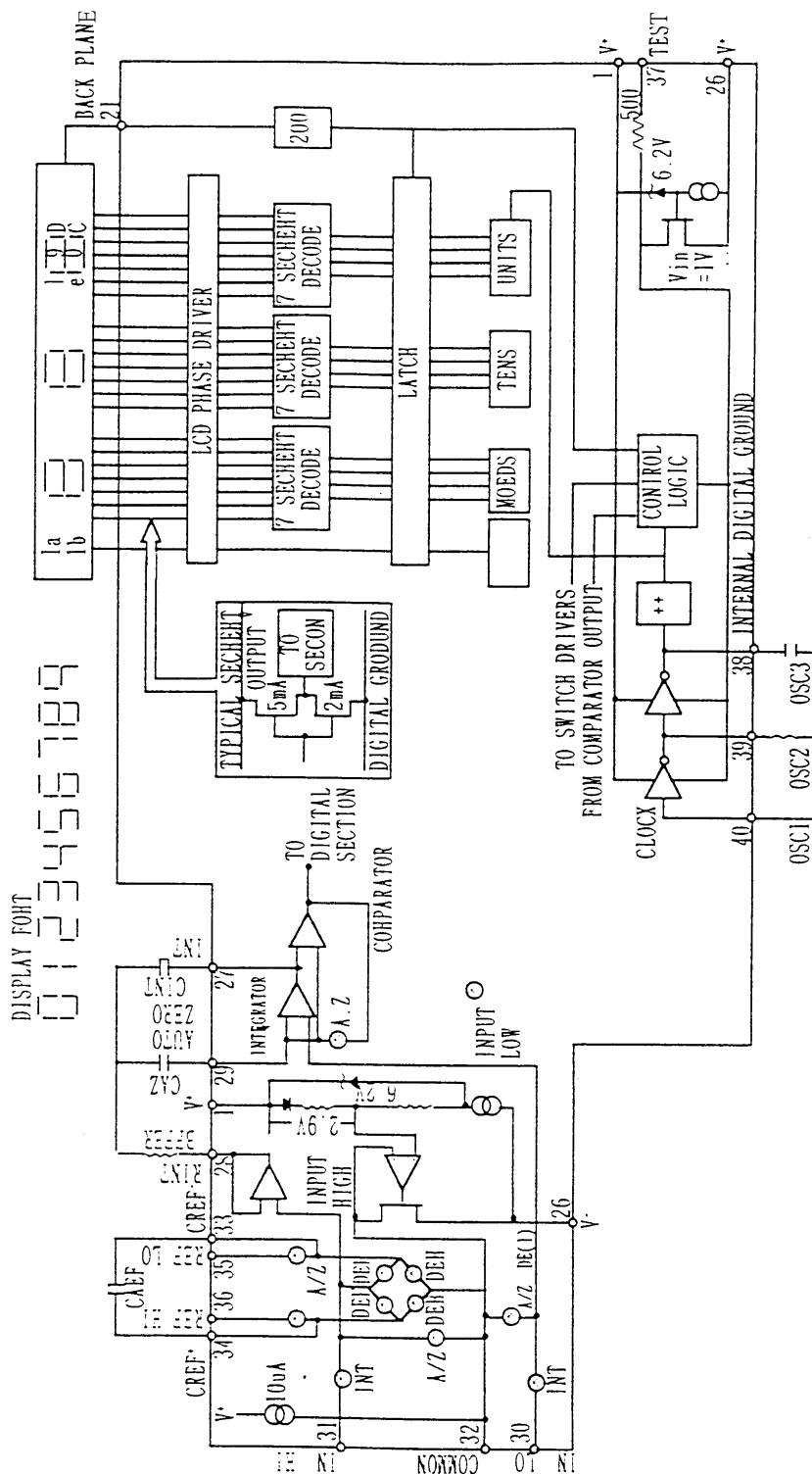
- ★ Guaranteed zero reading with zero input
- ★ Low input leakage current (1pA typical)
- ★ Internal Reference with low temperature drift (60ppm/°C typical)
- ★ Low noise (15 μ Vp-p typical)
- ★ Direct LCD display driver-no external components required
- ★ Differential input and voltage reference
- ★ Precision null detection with true polarity at zero
- ★ Internal clock circuit
- ★ No additional active circuits required

3 · APPLICATIONS

- ★ Digital panel meters
- ★ Digital multimeters
- ★ Thermometers
- ★ Capacitance meters
- ★ pH meters
- ★ Photometers



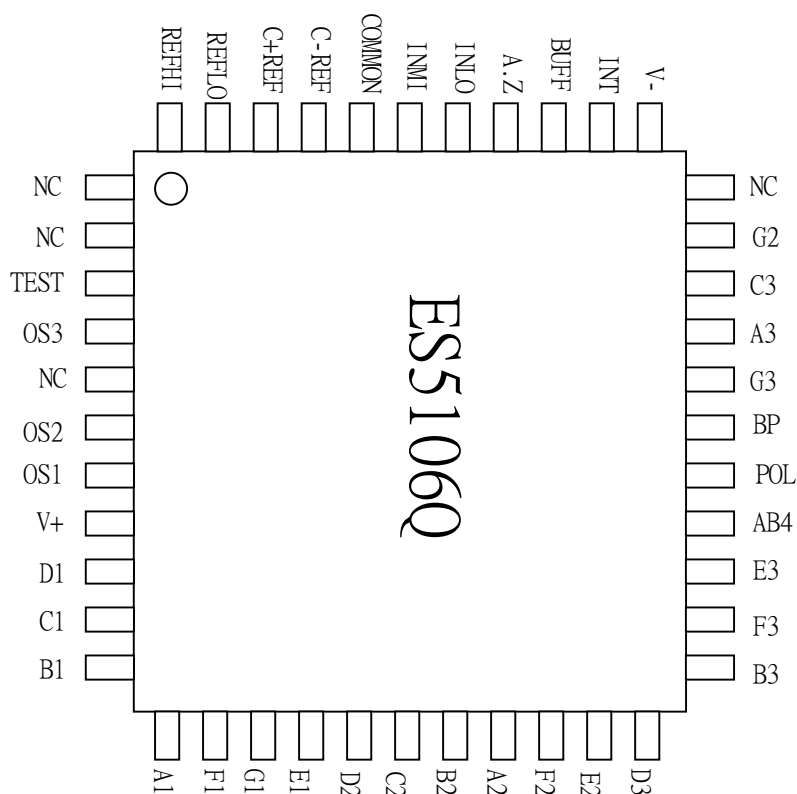
4 · BLOCK DIAGRAM





4 · PIN ASIGNMENT

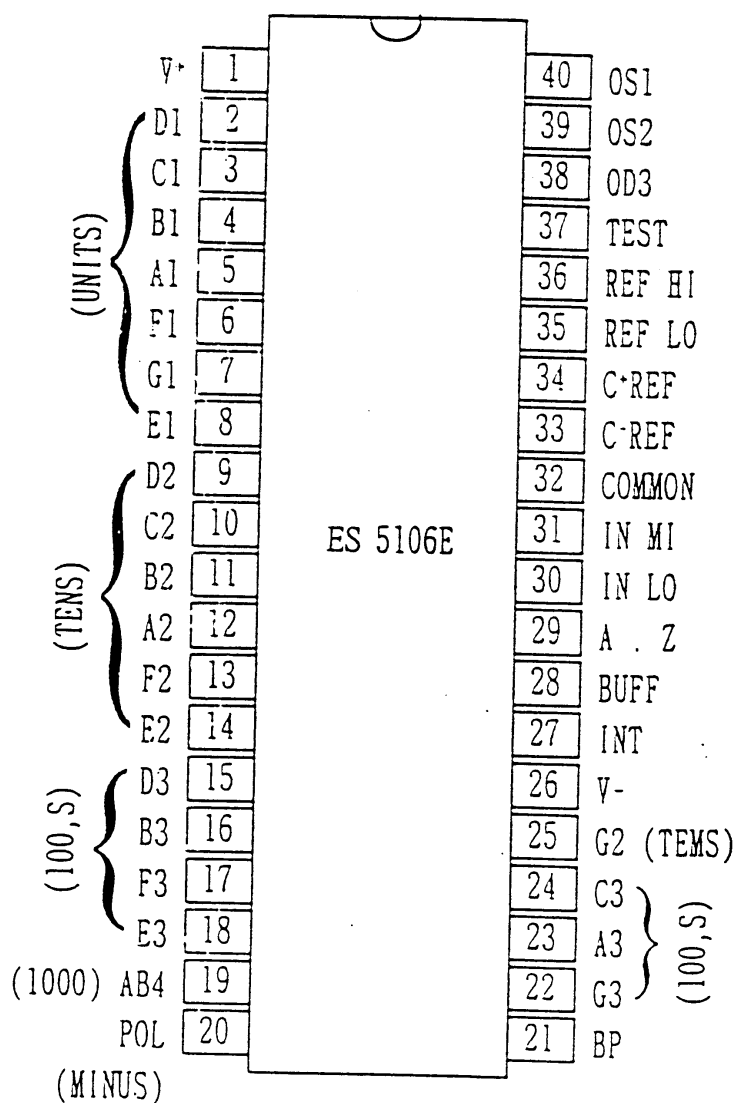
44-pin QFP package





PIN ASSIGNMENT

40-pin DIP package





5 · Pin Description

Pin No	Symbol	Description
1	V+	Positive supply voltage. Connecting to battery positive terminal.
2	D1	LCD segment line.
3	C1	LCD segment line.
4	B1	LCD segment line.
5	A1	LCD segment line.
6	F1	LCD segment line.
7	G1	LCD segment line.
8	E1	LCD segment line.
9	D2	LCD segment line.
10	C2	LCD segment line.
11	B2	LCD segment line.
12	A2	LCD segment line.
13	F2	LCD segment line.
14	E2	LCD segment line.
15	D3	LCD segment line.
16	B3	LCD segment line.
17	F3	LCD segment line.
18	E3	LCD segment line.
19	AB4	LCD segment line.
20	POL	LCD segment line.
21	BP	LCD Backplane.
22	G3	LCD segment line.
23	A3	LCD segment line.
24	C3	LCD segment line.
25	G2	LCD segment line.
26	V-	Negative supply voltage. Connecting to battery negative terminal.
27	INT	Integration cycle output.
28	BUFF	Integration resistor connection for buffer output.
29	A.Z	Auto-zero capacitor connection.
30	IN LO	Low analog input signal connection.
31	IN MI	High analog input signal connection.
32	COMMON	Set the common-mode voltage for the system
33	C+REF	Positive capacitor connection for on-chip DC-DC converter.
34	C-REF	Negative capacitor connection for on-chip DC-DC converter.
35	REF LO	Low differential reference input connection.
36	REF HI	High differential reference input connection.
37	TEST	Pull high to V+ all LCD segments will be activated.
38	OS3	Crystal oscillator connection.
39	OS2	Crystal oscillator connection.
40	OS1	Crystal oscillator connection.

6 · ABSOLUTE MAXIMUM RATINGS

Characteristic	Rating
Supply Voltage (V ⁺ to V ⁻)	12V
Analog Input Voltage (either input)	V ⁺ to V ⁻
Reference Input Voltage (either input)	V ⁺ to V ⁻
Clock Input	TEST to V ⁺
Power Dissipation (plastic package)	800mW
Operating Temperature	0°C to +70°C
Storage Temperature	-65°C to +160°C
Lead Temperature(soldering, 10 sec)	270°C

7 · ELECTRICAL CHARACTERISTICS

Characteristic	Test Condition	Limit			Units
		Min.	Typ.	Max.	
Zero Input Reading	V _{IN} =0.0V Full-Scale=200.0mV	-000.0	±000.0	+000.0	Digital Reading
Ratiometric Reading	V _{IN} =V _{REF} , V _{REF} =100mV	999	999/1000	1000	Digital Reading
Linearity (Max. deviation from best straight line fit)	Full-Scale=200mV or Full-Scale=2.000V	-1	±0.2	1	Counts



ELECTRICAL CHARACTERISTICS (continued)

Characteristic	Test Condition	Limit			Units
		Min.	Typ.	Max.	
Roll-Over Error	$-V_{IN}=+V_{IN} \sim 200.0mV$	-1	± 0.2	+1	Counts
Common Mode Rejection Ratio	$V_{CM}=\pm 1V, V_{IN}=0V$ Full-Scale=200.0mV	—	50	—	$\mu V/V$
Noise	$V_{IN}=0V$, Full-Scale=200.0mV	—	15	—	$\mu Vp-p$
Input Leakage Current	$V_{IN}=0V$	—	1	10	pA
Zero Reading Drift	$V_{IN}=0V, 0^{\circ}C \leq T_A \leq +70^{\circ}C$	—	0.2	1	$\mu V/^{\circ}C$
Scale Factor Temperature Coefficient	$V_{IN}=199.0mV, 0^{\circ}C \leq T_A \leq +70^{\circ}C$ Ext.Ref.=0ppm/ $^{\circ}C$	—	1	5	ppm/ $^{\circ}C$
Analog COMMON Voltage (with respect to V^+)	25K Ω Between Common and Positive Supply	2.8	3.0	3.2	V
Analog COMMON Temperature Coefficient	25K Ω Between Common and $V^+, 0^{\circ}C \leq T_A \leq 70^{\circ}C$	—	60	75	ppm/ $^{\circ}C$
Segment Drive Voltage	V^+ to V^- =9V	4	5	6	V
Back plane Drive Voltage	V^+ to V^- =9V	4	5	6	V
Supply Current (Does not include COMMON current)	$V_{IN}=0V$	—	0.5	0.65	mA



8 · Operation Mode

★ Analog Common

The Common pin is used to set the common-mode voltage for the system in which the input signals are floating with respect to the power supply of the ES5106. In all most of the applications, IN LO, REF LO and COMMON pins are tied to the same point, so that the common mode voltage can be removed from the reference system and the converter. In some applications, IN LO may not at the same point with COMMON and thus a common mode voltage exists in the system, the high CMRR (86db typical) of the ES 5106 can take care of this common mode voltage. Nevertheless, it should be care to prevent the output of the integrator from saturation.

The COMMON pin is also used as a voltage reference. It sets a voltage which is around 2.9 volts more negative than the positive supply. The COMMON voltage of ES5106 has a 0.001 %/% voltage coefficient and a low output impedance of 15Ω typical.

The analog COMMON is tied internally to an N channel FET capable of sinking 30mA. This FET will hold the COMMON voltage at 2.9 volts when an external load attempt to pull the COMMON voltage toward the positive supply.



The source current of COMMON is only $10\ \mu\text{A}$, so it is easy to pull COMMON voltage to a more negative voltage with respect to the positive supply.

When the total supply voltage is large enough to cause the zener to regulate ($>7\text{V}$), the COMMON voltage will have a low temperature coefficient typically less than $60\ \text{ppm}/^\circ\text{C}$. This voltage can be used to generate the ES5106 reference voltage and an external voltage reference will be unnecessary in most cases.

★ Reference Voltage

For a 1000 counts reading, the input signal must be equal to the reference voltage. So for a 2000 counts full-scale reading, it requires the input signal be twice the reference voltage. Thus, for the 200mV and 2.000V full-scale, the reference voltage should equal 100.0mV and 1.000V. In some applications the full-scale input voltage may be other than 200mV or 2V, but 600mV, for example, The reference voltage should be set to 300 mV and the input signal can be used directly without being divided.

The differential reference can be used during the measurement of resistor by the ratiometric method and when a digital reading of zero is desired for $V_{\text{IN}} \neq 0$. A compensating offset voltage can be applied between COMMON and IN LO and the voltage of being measured is connected between COMMON and IN HI.



★ System Timing

The oscillator frequency is divided by four prior to clocking the internal decade counters. The signal integrate takes a fixed 1000 counts time period which is equal to 4000 clock pulses. The back plane drive signal is derived by dividing clock frequency by 800. To make a maximum rejection of line frequency (60Hz or 50Hz) noise pickup, the signal integrate period should be a multiple of the line frequency period. For 60Hz noise rejection, oscillator frequencies of 120KHz, 80KHz, 60KHz, 48KHz, 40KHz, etc. should be selected. For 50Hz rejection, oscillator frequencies of 100KHz, 50KHz, 40KHz, etc. would be suitable.

For all ranges of frequency R_{osc} should be $100K\Omega$, C_{osc} is selected from the approximate equation $f=0.45/RC$. For 48KHz clock (3readings/second), $C_{osc}=100PF$.

★ Integrating Resistor

The input buffer amplifier and integrator both have class A output stage with $100\mu A$ of quiescent current and can supply $20\mu A$ drive currents with negligible linearity errors. The integrating resistor should be chosen to remain in the output stage linear drive region. It should be noticed that the integrating resistor should not be so large such that the leakage currents of printed circuit board will induce errors. For a 200mV full-scale the recommended integrating resistor value is $47K\Omega$ and for 2V full-scale is $470K\Omega$.



★ Integrating Capacitor

The integrating capacitor should be selected to maximize integrator output voltage swing without causing output saturation. If the analog COMMON is used as voltage reference, a $\pm 2V$ full-scale integrator output swing is satisfactory. For 3 readings/second (48KHz clock) a $0.22 \mu F$ value of C_{INT} is suggested. When different oscillator frequencies are used, C_{INT} must be changed in inverse proportion to maintain the nominal $\pm 2V$ integrator swing.

The integrating capacitor should have low dielectric absorption to minimize roll-over error. An inexpensive polypropylene capacitor will work well.

★ Auto-Zero Capacitor

The auto-zero capacitor size has some influence on system noise. A $0.47 \mu F$ capacitor is recommended for 200mV full scale where noise is very important. A $0.047 \mu F$ capacitor is adequate for 2V full scale applications. A mylar type dielectric capacitor is adequate.

★ Reference Voltage Capacitor

When IN LO is tied to analog COMMON, a $0.1 \mu F$ capacitor adequate to be the reference capacitor. If a large common-mode voltage exists and the application require a 200mV full scale, a larger value is required to prevent roll-over error. A $1.0 \mu F$ capacitor will hold the roll-over error to 0.5 count.



★ TEST

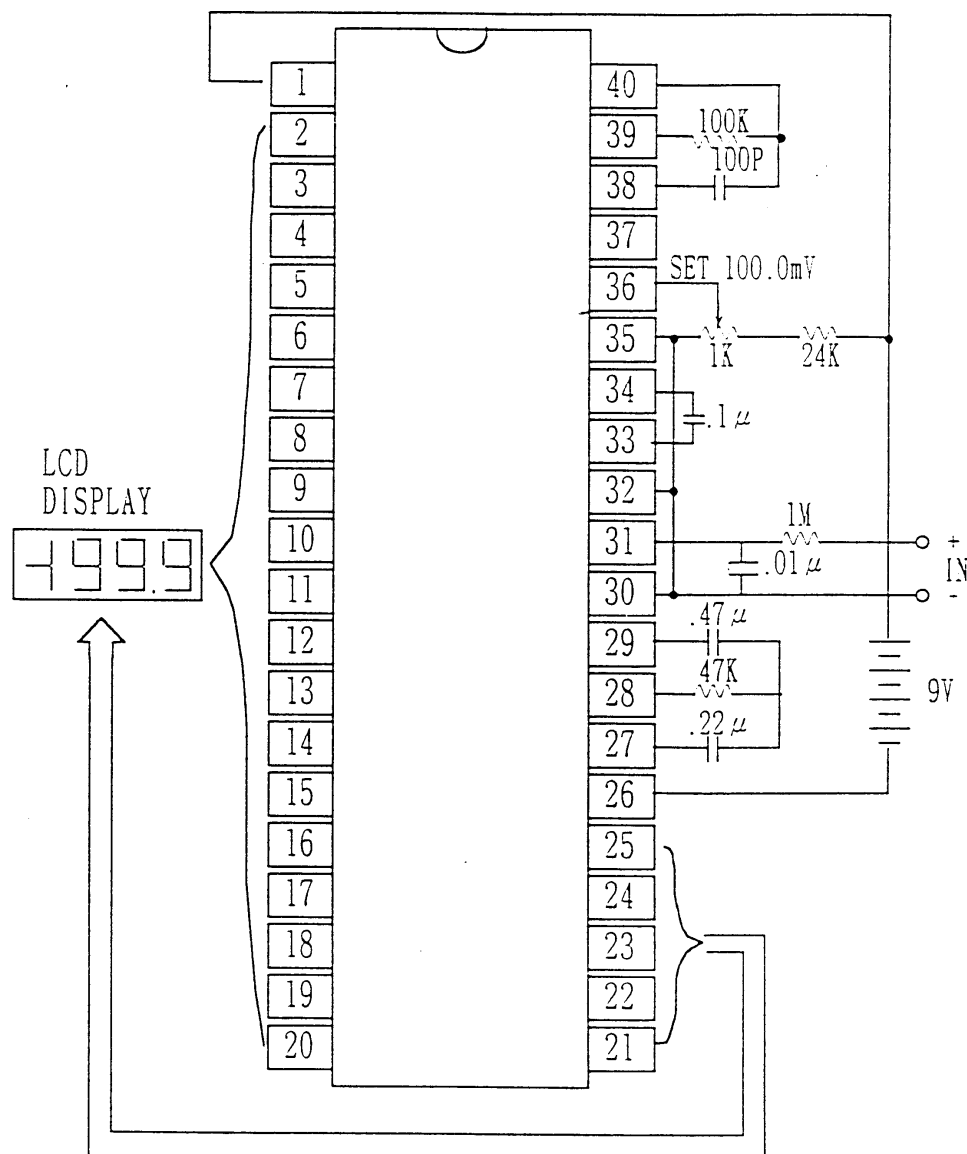
The TEST pin is tied to the internally generated digital supply through a 500Ω resistor. It's potential is 5V less than V^+ . Thus TEST may be used as the negative power supply connection for externally generated segment drivers. The TEST pin load should be no more than 1 mA.

If TEST is pulled high to V^+ all segments plus the minus sign will be activated and the display should read-1888. For such operation, the segment have a constant DC voltage and may destroy the LCD display if left in this mode for several minutes.

★ Segment Drivers

For 3 readings/second (48KHz clock) the BP frequency is a 60Hz square wave with a nominal amplitude of 5V. The segments are driven at the same frequency and amplitude and are in phase with BP when OFF, but out of phase when ON. In all cases negligible DC voltage exists across the segments. The polarity indication is "ON" for negative voltage inputs.

9 · TEST CIRCUIT

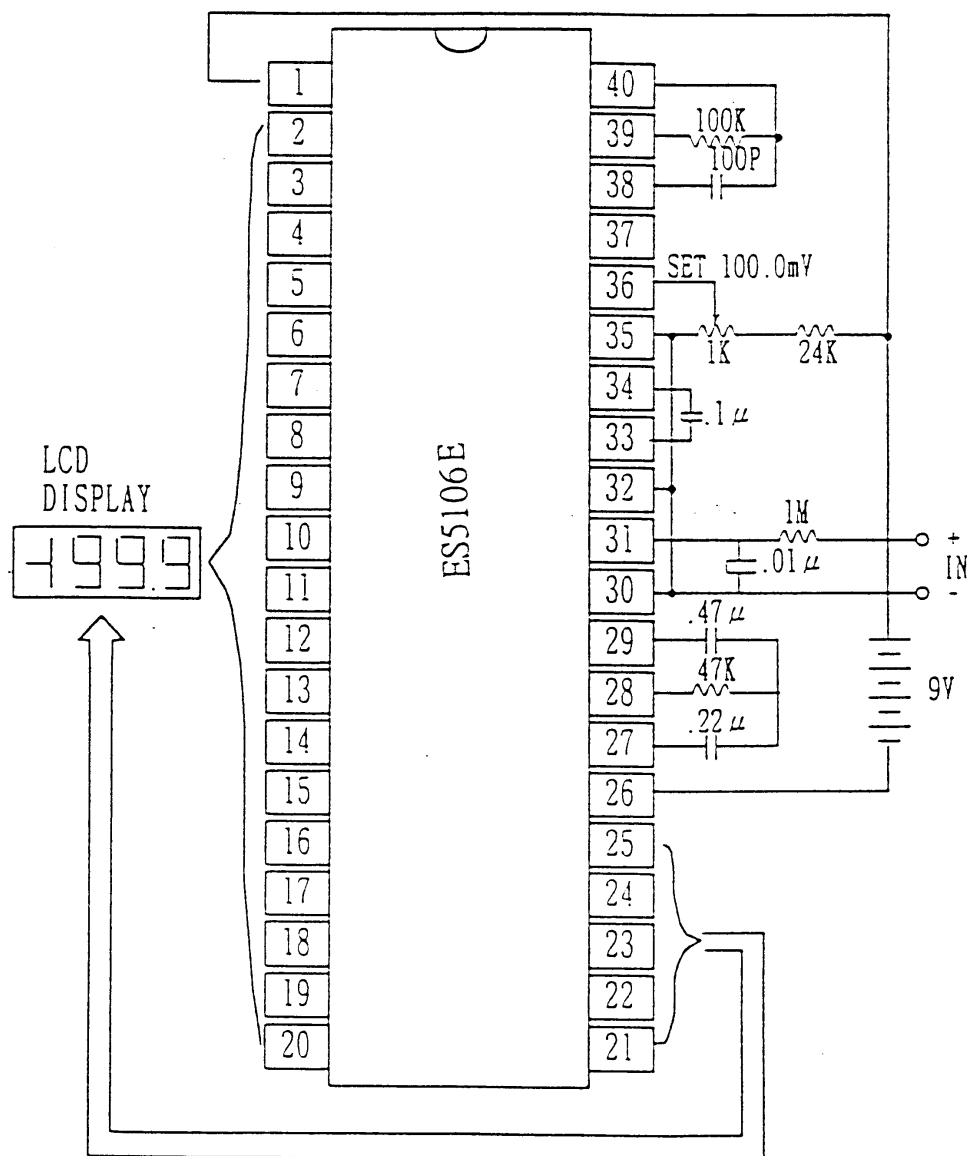


Clock Frequency 48 KHz (3 readings/sec)

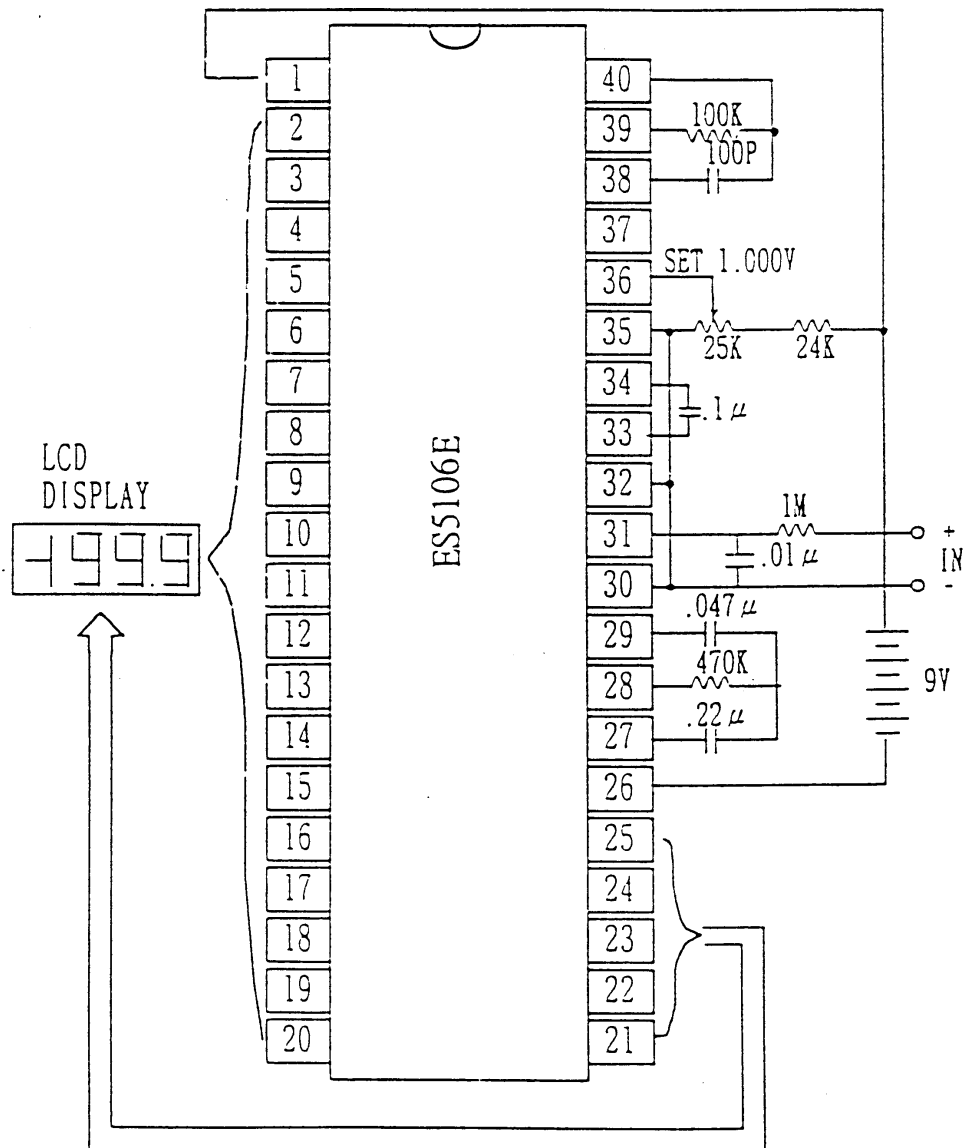
1 0 · APPLICATION CIRCUITS

(1) This circuit uses analog COMMON voltage as reference voltage.

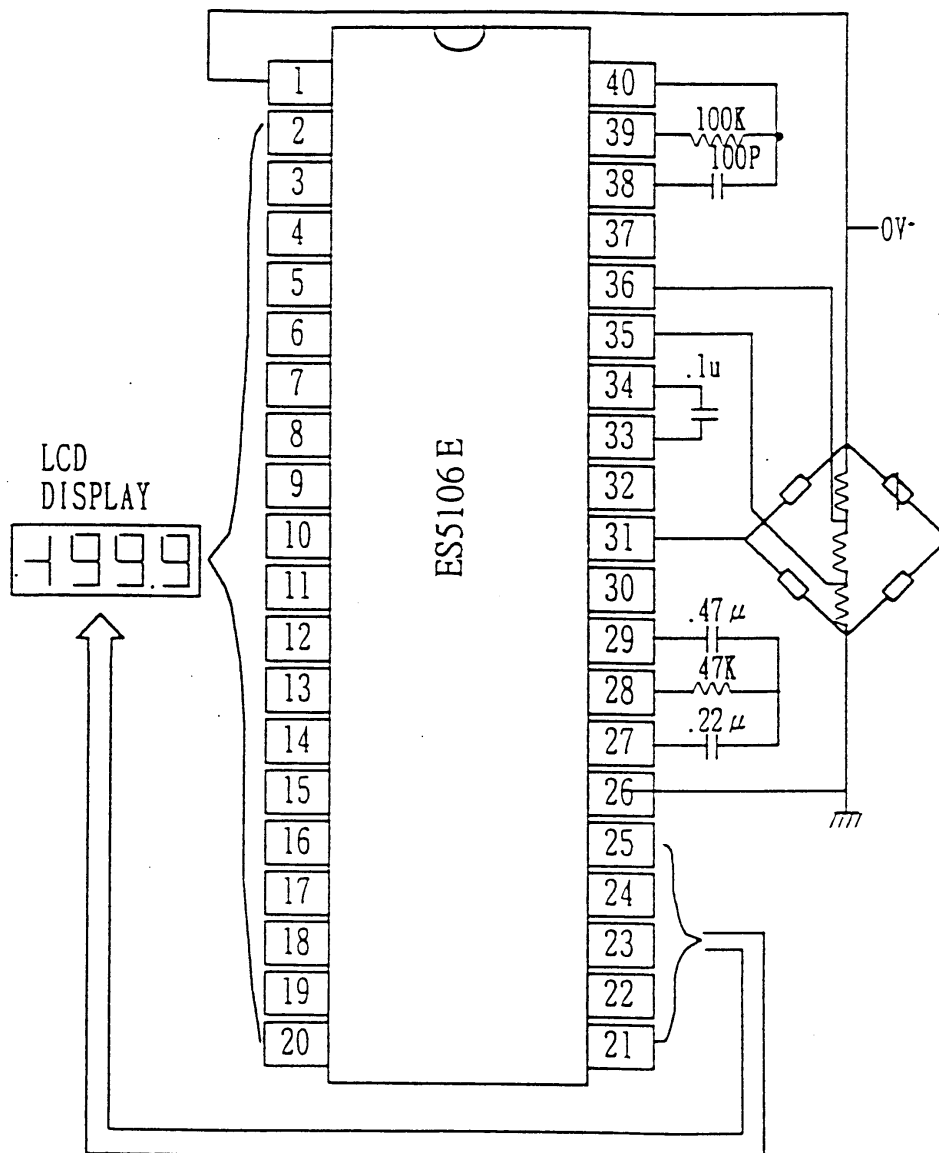
Values here are for 200.0mV full scale, 3 readings/sec.



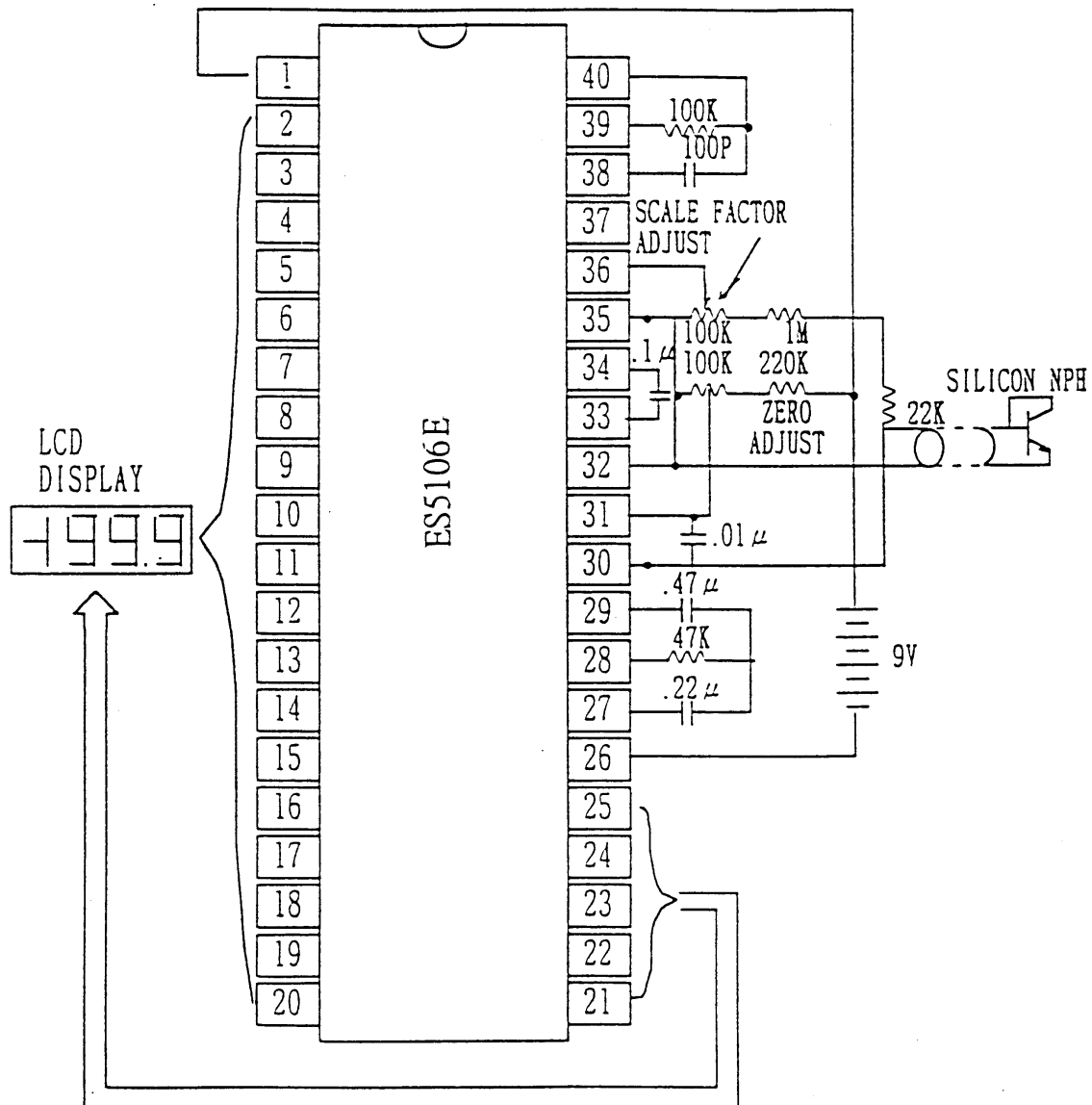
(2) The values of this circuit are for 2.000V full scale, 3 readings/sec.



(3) The circuit is for measuring ratiometric values of quad loadcell.



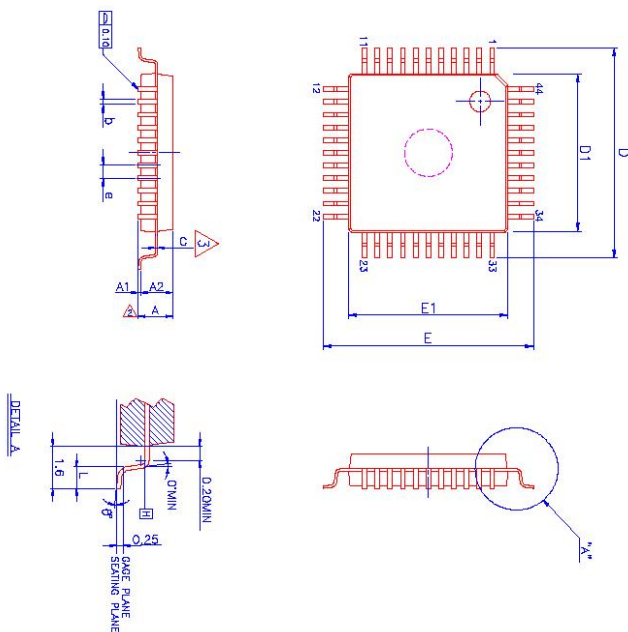
- (4) This circuit is a digital centigrade thermometer. The temperature sensor is a silicon diode-connected transistor which has a temperature coefficient of about $-2\text{mV}/^{\circ}\text{C}$.





1 1 · 包裝(Package)

44-pin QFP package



SYMBOLS	MIN.	NOM	MAX.
A	—	—	2.7
A1	0.25	0.30	0.35
A2	1.9	2.0	2.2
b	0.3 (TYP.)		
D	13.00	13.20	13.40
D1	9.9	10.00	10.10
E	13.00	13.20	13.40
E1	9.9	10.00	10.10
L	0.73	0.88	0.93
e	0.80 (TYP.)		
g	0	—	7
C	0.1	0.15	0.2

UNIT : mm

NOTES:

- 1.JEDEC OUTLINE:MO-108 AA-1
- 2.DATUM PLANE [H] IS LOCATED AT THE BOTTOM OF THE MOLD PARTING LINE COINCIDENT WITH WHERE THE LEAD EXITS THE BODY.
- 3.DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS 0.25 mm PER SIDE. DIMENSIONS D1 AND E1 DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE [H].
- 4.DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION.



40-pin DIP package

	MILLIMETERS		
DIM	MIN	MAX	
A	50.29	51.82	
B	15.49	16.00	
C	3.81	5.08	
D	0.41	0.51	
F	1.27 TYP		
G	2.54 BASIC		
H	0.76	1.78	
J	0.23	0.30	
K	3.94	4.95	
L	15.24 BASIC		
N	1.02	1.52	

